

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/701,530	LEE ET AL.		
Examiner	Art Unit		
Cam N. Nguyen	1754		

SEARCHED						
Class	s	Subclass	Date		Examiner	
600		38	12/16	105		CM
	1	323				
		327-3	29			
		331 33	2_			
		334, 33 344-3	9-342	1	i	
		344-3	46			
		355				
		415				
7		439	'	j		
				- 1		- 1

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
<u></u>					
· · · · ·					
			L		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See attached Search history Inventor Name Dearched	p-/16/05	enn		
France Dearched	12/16/ps	-an		